

<b>Notice of References Cited</b>		Application/Control No. 10/039,333	Applicant(s)/Patent Under Reexamination LEE ET AL.	
		Examiner Binh X Tran	Art Unit 1765	Page 1 of 1

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L	US-			
M	US-			

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**NON-PATENT DOCUMENTS**

*	Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)	
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